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## ESD TESTING REQUEST FORM

(Please fill the information in the white fields, double click the small box and check it to mark your selection)

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| --- | --- | --- | --- |
| **Company**: |  | **Location:** |  |
| **Contact Name:** |  | **Email:** |  |
| **Phone No:** |  | **Date:** |  |
| **Part Number:** |  | **Lot#/Date Code:** |  |

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| 1. Test required: | HBM CDM MM | | | | | | | | | | | | | | |
| 2. ESD Industry STD: | JEDEC Mil-Std 883 ESDA Customer specific, please specify: **(Default: JEDEC)** | | | | | | | | | | | | | | |
| 3. Package type: |  | | | | | | | | | | |
| 4. Number of pins: |  | | | | | | | | | | |
| 5. PKG Pin/Ball Pitch: |  | | | | | | | | | | |
| 6. Please provide pin-list and package drawing: | | | | | | |  | | | | |
| 7. Number of no connect pins: | | |  | | | | | | | | |
| 8. Total number of internally separated supply pins: | | | | | | | |  | | | |
| 9. Total number of internally separated ground pins: | | | | | | | |  | | | |
| 10. Sample size per voltage(s) (HBM): | | | | | |  | | | | | | | | | | | | |
| 11. Sample size per voltage(s) (CDM): | | | | | |  | | | | | | | | | | | | |
| 12. Sample size per voltage(s) (MM): | | | | | |  | | | | | | | | | | | | |
| 13. Voltage level(s) for HBM:  (ie: +/-1kV, +/-2kV, etc..) | | | |  | | | | | | | | | | | | | | |
| 14. Voltage level(s) for CDM:  (ie: +/-250V, +/-500V, etc..) | | | |  | | | | | | | | | | | | | | |
| 15. Voltage level(s) for MM:  (ie: +/-100V, +/-200V, etc..) | | | |  | | | | | | | | | | | | | | |
| **(For 13, 14 and 15 above Default voltage level, if not specified: HBM +/-2000V, CDM +/-500V, MM +/-250V)** | | | | | | | | | | | | | | | | | | |
| 16. Are both polarities required: | | | | | Yes No | | | | | (typically ”Yes”) | | | If “No”, which: | |  | | | |
| 17. Pre and Post curve testing required: Yes No. If “Yes” please specify line 18 for Curve Trace parameters  **(Default: Force current, +/-100uA, and measure voltage)**  **(Pass/Fail Criteria: 25% shift from initial I-V reading)** | | | | | | | | | | | | | | | | | | |
| ***# For Curve Tracing: Please specify information in (18.) below, if default criterias above are not acceptable.*** | | | | | | | | | | | | | | | | | | |
| 18. Please specify Current **OR** Voltage mode | | Force Current (mA): | | | | | | |  | | Voltage Limit: | | |  | | | V |
| Force Voltage (V): | | | | | | |  | | Current Limit: | | |  | | | mA |
| Pass / Fail delta (%): | | | | | | |  | |

1. Mil-Std, EOS/ESD (HBM) = 3 pulses: JEDEC (HBM,MM) = 1 pulse: JEDEC (CDM) = 3 pulses.
2. Mil-Std, EOS/ESD (HBM) = 1 sec delay : JEDEC (HBM,MM) = 0.5 sec delay: JEDEC (CDM) = 1 sec delay.
3. PASS/FAIL criterion is determined via the Pre and Post curve testing (leakage testing). Curve testing may be a method to determine PASS/FAIL. However, we recommended that customer perform their own device ELECTRICAL TEST (via ATE) to determine PASS/FAIL. Curve Testing **SHOULD NOT** **BE** used for **DEVICE QUALIFICATION** purposes.